

This listing of claims replaces all prior versions, and listings of claims in the instant application:

Listing of Claims:

1. (Cancelled) Please Cancel Claim 1, without prejudice.
2. (Cancelled) Please Cancel Claim 2, without prejudice.
3. (Cancelled) Please Cancel Claim 3, without prejudice.
4. (Currently Amended) ~~The boosted memory array of Claim 2, A boosted memory array comprising:~~
at least one bitline;
at least one memory cell coupled to said bitline;
a bitline booster circuit coupled to said bitline;
a bitline booster circuit bitline boost enable signal input terminal coupled to said bitline booster circuit;
a bitline boost enable signal coupled to said bitline booster circuit bitline boost enable signal input terminal,
wherein;

when said bitline boost enable signal is active
and a signal on said at least one bitline starts
going low, said bitline booster circuit discharges
said at least one bitline, further wherein;

said boosted memory array includes at least two
bitlines, a first bitline and a second bitline, further
wherein;

said bitline booster circuit comprises:

a first NOR gate, a first input of said first NOR gate being coupled to said first bitline and a second input of said first NOR gate being coupled to said bitline boost enable signal;

a first transistor, an output of said first NOR gate being coupled to a control electrode of said first transistor, a first flow electrode of said first transistor being coupled to said first bitline, a second flow electrode of said first transistor being coupled to a supply voltage;

a second NOR gate, a second input of said second NOR gate being coupled to said second bitline and a second input of said second NOR gate being coupled to said bitline boost enable signal; and

a second transistor, an output of said second NOR gate being coupled to a control electrode of said second transistor, a first flow electrode of said second transistor being coupled to said second bitline, a second flow electrode of said second transistor being coupled to said supply voltage.

5. (Original) The boosted memory array of Claim 4, wherein;

 said first and second transistors are NFETS and said supply voltage is ground.

6. (Original) The boosted memory array of Claim 4, wherein;

 said boosted memory array is on the same silicon chip as a microprocessor.

7. (Cancelled) Please Cancel Claim 7, without prejudice.

8. (Cancelled) Please Cancel Claim 8, without prejudice.

9. (Cancelled) Please Cancel Claim 9, without prejudice.

10. (Currently Amended) ~~The microprocessor chip of Claim 9,~~ A microprocessor chip, said microprocessor chip comprising:

one or more functional blocks; and

a boosted memory array, said boosted memory array comprising:

at least one bitline;

at least one memory cell coupled to said bitline;

a bitline booster circuit coupled to said bitline;

a bitline booster circuit bitline boost enable signal input terminal coupled to said bitline booster circuit;

a bitline boost enable signal coupled to said bitline booster circuit bitline boost enable signal input terminal,

wherein;

when said bitline boost enable signal is active and a signal on said at least one bitline starts going low, said bitline booster circuit discharges said at least one bitline, further wherein:

said boosted memory array includes at least two bitlines, a first bitline and a second bitline, further wherein;

said bitline boost enable signal is active only during write operation, further wherein;

said bitline booster circuit comprises:

a first NOR gate, a first input of said first NOR gate being coupled to said first bitline and a second input of said

first NOR gate being coupled to said bitline boost enable signal;

 a first transistor, an output of said first NOR gate being coupled to a control electrode of said first transistor, a first flow electrode of said first transistor being coupled to said first bitline, a second flow electrode of said first transistor being coupled to a supply voltage;

 a second NOR gate, a first input of said second NOR gate being coupled to said second bitline and a second input of said second NOR gate being coupled to said bitline boost enable signal; and

 a second transistor, an output of said second NOR gate being coupled to a control electrode of said second transistor, a first flow electrode of said second transistor being coupled to said second bitline, a second flow electrode of said second transistor being coupled to said supply voltage.

11. (Original) The microprocessor chip of Claim 10, wherein;

 said first and second transistors are NFETS and said supply voltage is ground.

12. (Cancelled) Please Cancel Claim 12, without prejudice.

13. (Cancelled) Please Cancel Claim 13, without prejudice.

14. (Cancelled) Please Cancel Claim 14, without prejudice.

15. (Currently Amended) ~~The method for boosting the performance of a memory array of Claim 14, A method for boosting the performance of a memory array comprising:~~

providing at least one bitline;

coupling at least one memory cell to said at least one bitline;

coupling a bitline booster circuit to said at least one bitline;

coupling a bitline booster circuit bitline boost enable signal input terminal to said bitline booster circuit;

coupling a bitline boost enable signal to said bitline booster circuit bitline boost enable signal input terminal,
such that;

when said bitline boost enable signal is active and a signal on said at least one bitline starts going low, said

bitline booster circuit discharges said at least one bitline,
wherein;

said boosted memory array includes at least two bitlines,
a first bitline and a second bitline, further wherein;

said bitline boost enable signal is active only during
write operation, further wherein;

 said bitline booster circuit comprises:

 a first NOR gate, a first input of said first NOR gate being coupled to said first bitline and a second input of said first NOR gate being coupled to said bitline boost enable signal;

 a first transistor, an output of said first NOR gate being coupled to a control electrode of said first transistor, a first flow electrode of said first transistor being coupled to said first bitline, a second flow electrode of said first transistor being coupled to a supply voltage;

 a second NOR gate, a first input of said second NOR gate being coupled to said second bitline and a second input of said second NOR gate being coupled to said bitline boost enable signal; and

 a second transistor, an output of said second NOR gate being coupled to a control electrode of said second transistor, a first flow electrode of said second transistor being coupled to said second bitline, a second flow electrode of said second transistor being coupled to said supply voltage.

16. (Original) The method for boosting the performance of a memory array of Claim 15, wherein;

 said first and second transistors are NFETS and said supply voltage is ground.

17. (Original) The method for boosting the performance of a memory array of Claim 15, wherein;

 said boosted memory array is on the same silicon chip as a microprocessor.

18. (Cancelled) Please Cancel Claim 18, without prejudice.

19. (Cancelled) Please Cancel Claim 19, without prejudice.

20. (Cancelled) Please Cancel Claim 20, without prejudice.

21. (Currently Amended) ~~The method for improving the performance of a microprocessor chip of Claim 20, A method for improving the performance of a microprocessor chip, said method comprising:~~

providing one or more functional blocks on said microprocessor chip;

providing a boosted memory array, said boosted memory array comprising:

at least one bitline;

at least one memory cell coupled to said bitline;

a bitline booster circuit coupled to said bitline;

a bitline booster circuit bitline boost enable signal input terminal coupled to said bitline booster circuit;

a bitline boost enable signal coupled to said bitline booster circuit bitline boost enable signal input terminal, wherein;

when said bitline boost enable signal is active and a signal on said at least one bitline starts going low, said bitline booster circuit discharges said at least one bitline, further wherein;

said bitline boost enable signal is active only during write operation, further wherein;

said bitline booster circuit comprises:

a first NOR gate, a first input of said first NOR gate being coupled to said first bitline and a second input of said

first NOR gate being coupled to said bitline boost enable signal;

 a first transistor, an output of said first NOR gate being coupled to a control electrode of said first transistor, a first flow electrode of said first transistor being coupled to said first bitline, a second flow electrode of said first transistor being coupled to a supply voltage;

 a second NOR gate, a first input of said second NOR gate being coupled to said second bitline and a second input of said second NOR gate being coupled to said bitline boost enable signal; and

 a second transistor, an output of said second NOR gate being coupled to a control electrode of said second transistor, a first flow electrode of said second transistor being coupled to said second bitline, a second flow electrode of said second transistor being coupled to said supply voltage.

22. (Original) The method for improving the performance of a microprocessor chip of Claim 21, wherein; said first and second transistors are NFETS and said supply voltage is ground.